Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/853,661	TANAKA, MASA	AHIRO
Examiner	Art Unit	
José R. Díaz	2815	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
NPL search: JPO Website (Translation of three references of IDS filed 6/8/05)	8/30/2005	JRD	